

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

INFORMATION DISCLOSURE STATEMENT		Docket Number 10191/1614	
Application Number To Be Assigned	Filing Date Herewith	Examiner To Be Assigned	Art Unit To Be Assigned
Title METHOD FOR ELIMINATING DEFECTS IN SILICON ELEMENTS THROUGH SELECTIVE ETCHING		Applicant(s) Richard SPITZ et al.	

Address to:
Assistant Commissioner
for Patents
Washington, D.C. 20231

1. In accordance with the duty of disclosure under 37 C.F.R. § 1.56 and in conformance with the procedures of 37 C.F.R. §§ 1.97 and 1.98 and M.P.E.P. § 609, attorneys for Applicant(s) hereby bring the following reference(s) to the attention of the Examiner. The reference(s) are listed on the attached modified PTO Form No. 1449. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the reference(s) be made of record therein and appear among the "References Cited" on any patent to issue therefrom.
2. A copy of each patent, publication or other information listed on the modified PTO form 1449 is enclosed, except as otherwise indicated on the modified PTO form 1449.

Dated: 12/25/80

By: Richard L. Mayer
Richard L. Mayer (Reg. No. 22,490)

KENYON & KENYON
One Broadway
New York, N.Y. 10004
(212) 425-7200 (telephone)
(212) 425-5288 (facsimile)

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT
PTO FORM 1449**

ATTY. DOCKET NO.
10191/1614

SERIAL NO.
Not yet assigned
08/728720

APPLICANT(s)

Richard SPITZ et al.

FILING DATE
Herewith

GROUP
Not yet assigned

U. S. PATENT DOCUMENTS

EXAMINER INITIAL	PATENT NUMBER	PATENT DATE	NAME	CLASS	SUBCLASS	FILING DATE
	5,693,182*	December 2, 1997	Mathuni			
	5,350,480*	September 27, 1994	Gray			

*Copy of reference is not enclosed because reference is cited in Search Report (copy of reference provided by International Searching Authority).

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION	
						YES	NO
	DE 35 06 995 *	28 August 1986	Fed. Rep. of Germany			X*	
	EP 0 878 824 *	24 April 1998	Europe			X*	
	JP 03 012921 ✓	21 January 1991	Japan			X*	
	JP 08 031785 *	2 February 1996	Japan			X*	

*Copy of reference is not enclosed because reference is cited and described in Search Report (copy of reference provided by International Searching Authority).

OTHER DOCUMENTS

EXAMINER INITIAL	AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.
	Patent Abstract of Japan, Vol. 015, No. 125 (1-1050) (27-3-91)*
	Patent Abstract of Japan, Vol. 1996, No. 06 (28/6/96)*

*Copy of reference is not enclosed because reference is cited and described in Search Report (copy of reference provided by International Searching Authority).

EXAMINER

DATE CONSIDERED